



FQB50N06 / FQI50N06

60V N-Channel MOSFET

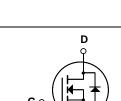
General Description

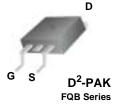
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

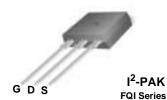
This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as automotive, DC/DC converters, and high efficiency switching for power management in portable and battery operated products.

Features

- 50A, 60V, $R_{DS(on)} = 0.022\Omega @V_{GS} = 10 V$
- Low gate charge (typical 31 nC)
- Low Crss (typical 65 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability
- 175°C maximum junction temperature rating
- · RoHS Compliant







Absolute Maximum Ratings

$T_C = 25^{\circ}C$	unless	otherwise	noted

Symbol	Parameter		FQB50N06 / FQI50N06	Units
V _{DSS}	Drain-Source Voltage		60	V
I _D	Drain Current - Continuous (T _C = 25°C)		50	Α
	- Continuous (T _C = 100°C	()	35.4	Α
I _{DM}	Drain Current - Pulsed	(Note 1)	200	Α
V _{GSS}	Gate-Source Voltage		± 25	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	490	mJ
I _{AR}	Avalanche Current	(Note 1)	50	Α
E _{AR}	Repetitive Avalanche Energy	(Note 1)	12	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	7.0	V/ns
P _D	Power Dissipation (T _A = 25°C) *		3.75	W
	Power Dissipation (T _C = 25°C)		120	W
	- Derate above 25°C		0.8	W/°C
T_J , T_{STG}	Operating and Storage Temperature Range		-55 to +175	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		1.24	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		40	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

^{*} When mounted on the minimum pad size recommended (PCB Mount)

Parameter	Test Conditions	3	Min	Тур	Max	Units
aracteristics						
Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		60			V
Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced	to 25°C		0.06		V/°C
Zero Onto Valta va Brain Orana d	V _{DS} = 60 V, V _{GS} = 0 V				1	μΑ
Zero Gate Voltage Drain Current	V _{DS} = 48 V, T _C = 150°C				10	μΑ
Gate-Body Leakage Current, Forward	V _{GS} = 25 V, V _{DS} = 0 V				100	nA
Gate-Body Leakage Current, Reverse	V _{GS} = -25 V, V _{DS} = 0 V				-100	nA
aracteristics						
Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		2.0		4.0	V
Static Drain-Source On-Resistance	V _{GS} =10 V, I _D =25 A			0.018	0.022	Ω
Forward Transconductance	V _{DS} = 25 V, I _D = 25 A	(Note 4)		22		S
Input Capacitance Output Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz			1180 440	1540 580	pF pF
Reverse Transfer Capacitance				65	90	pF
ing Characteristics						
, -	V 00 V I 05 A			15	40	ns
,	$V_{DD} = 30 \text{ V}, I_{D} = 25 \text{ A},$ $R_{G} = 25 \Omega$			105	220	ns
Turn-Off Delay Time				60	130	ns
Turn-Off Fall Time	((Note 4, 5)		65	140	ns
Total Gate Charge	$V_{DS} = 48 \text{ V}, I_{D} = 50 \text{ A},$ $V_{GS} = 10 \text{ V}$ (Note 4, 5)			31	41	nC
Gate-Source Charge				8		nC
Gate-Drain Charge				13		nC
		<u>'</u>		I.		
İ	<u>_</u>	S			50	A
						A
						V
Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_S = 50 \text{ A}$ $V_{GS} = 0 \text{ V}, I_S = 50 \text{ A},$		<u></u>	52	1.5	ns
	Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current Gate-Body Leakage Current, Forward Gate-Body Leakage Current, Reverse Bracteristics Gate Threshold Voltage Static Drain-Source On-Resistance Forward Transconductance Input Capacitance Output Capacitance Reverse Transfer Capacitance Reverse Transfer Capacitance Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Drain Charge Gate-Drain Charge Fource Diode Characteristics are Maximum Continuous Drain-Source Diode Forward Voltage Drain-Source Diode Forward Voltage	Aracteristics Drain-Source Breakdown Voltage $V_{GS} = 0 \text{ V}$, $I_D = 250 \text{ μA}$ Breakdown Voltage Temperature Coefficient $I_D = 250 \text{ μA}$, Referenced Zero Gate Voltage Drain Current $V_{DS} = 60 \text{ V}$, $V_{GS} = 0 \text{ V}$ VDS = 48 V, $T_C = 150^{\circ}\text{C}$ $V_{GS} = 25 \text{ V}$, $V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Forward $V_{GS} = 25 \text{ V}$, $V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = -25 \text{ V}$, $V_{DS} = 0 \text{ V}$ Gate Threshold Voltage $V_{DS} = V_{GS}$, $I_D = 250 \text{ μA}$ Static Drain-Source On-Resistance $V_{GS} = 10 \text{ V}$, $V_{DS} = 25 \text{ V}$, $V_{DS} = 25 \text{ V}$ Forward Transconductance $V_{DS} = 25 \text{ V}$, $V_{GS} = 0 \text{ V}$, $V_{DS} = 25 \text{ V}$ Forward Transconductance $V_{DS} = 25 \text{ V}$, $V_{GS} = 0 \text{ V}$, $V_{GS} = 0 \text{ V}$, $V_{DS} = 25 \text{ V}$, $V_{DS} = 25 \text{ V}$ Forward Transconductance $V_{DS} = 25 \text{ V}$, $V_{DS} = 0 \text{ V}$, $V_{DS} = 0 \text{ V}$, $V_{DS} = 0 \text{ V}$ Forward Transconductance $V_{DS} = 25 \text{ V}$, $V_{DS} = 0 $	Iracteristics Drain-Source Breakdown Voltage $V_{GS} = 0 \text{ V}$, $I_D = 250 \text{ μA}$ Breakdown Voltage Temperature Coefficient $I_D = 250 \text{ μA}$, Referenced to 25°C Zero Gate Voltage Drain Current $V_{DS} = 60 \text{ V}$, $V_{GS} = 0 \text{ V}$ Gate-Body Leakage Current, Forward Gate-Body Leakage Current, Reverse $V_{GS} = 25 \text{ V}$, $V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = -25 \text{ V}$, $V_{DS} = 0 \text{ V}$ Iracteristics $V_{GS} = 10 \text{ V}$, $V_{DS} = 25 \text{ V}$, $V_{DS} = 0 \text{ V}$ Iracteristics $V_{DS} = V_{GS}$, $V_{DS} = 25 \text{ V}$, $V_{DS} = 0 \text{ V}$ Iracteristics $V_{DS} = 10 \text{ V}$, $V_{DS} = 25 \text{ A}$, (Note 4) Iracteristics $V_{DS} = 25 \text{ V}$, $V_{GS} = 0 \text{ V}$, $V_{DS} = 25 \text{ V}$, $V_{DS} = 0 \text{ V}$, $V_{DS} = 25 \text{ V}$, $V_{DS} = 0 \text{ V}$, $V_{DS} = 25 \text{ V}$, $V_{DS} = 0 \text{ V}$, $V_{DS} =$	Tracteristics Drain-Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current Gate-Body Leakage Current, Forward Gate-Body Leakage Current, Reverse Gate-Body Leakage Current, Reverse Gate Threshold Voltage V _{DS} = V _S , V _{DS} = 0 V V _{DS} = 25 V, V _{DS} = 0 V Tracteristics Gate Threshold Voltage V _{DS} = V _S , V _{DS} = 0 V V _{DS} = 25 V, V _{DS} = 0 V Tracteristics Gate Threshold Voltage V _{DS} = V _S , V _{DS} = 0 V V _{DS} = 25 V, V _{DS} = 0 V Tracteristics Gate Threshold Voltage V _{DS} = V _S , V _D = 250 μA 2.0 Static Drain-Source On-Resistance V _{DS} = 25 V, V _D = 25 A (Note 4) Torward Transconductance V _{DS} = 25 V, V _D = 25 A (Note 4) Toryard Transconductance V _{DS} = 25 V, V _D = 25 A (Note 4) Toryard Transfer Capacitance Turn-On Delay Time Turn-On Delay Time Turn-Off Delay Time Turn-Off Delay Time Turn-Off Pall Time Turn-Off Sate Charge Gate-Source Charge Gate-Source Charge Gate-Drain Charge (Note 4, 5) Tource Diode Characteristics and Maximum Ratings Maximum Continuous Drain-Source Diode Forward Current Drain-Source Diode Forward Voltage V _{SS} = 0 V, I _S = 50 A Torin-Source Diode Forward Current Drain-Source Diode Forward Voltage V _{SS} = 0 V, I _S = 50 A Torin-Source Diode Forward Voltage V _{SS} = 0 V, I _S = 50 A Torin-Source Diode Forward Voltage V _{SS} = 0 V, I _S = 50 A Torin-Source Diode Forward Voltage V _{SS} = 0 V, I _S = 50 A	racteristics Drain-Source Breakdown Voltage V _{GS} = 0 V, I _D = 250 μA 60 Breakdown Voltage Temperature Coefficient I _D = 250 μA, Referenced to 25°C 0.06 Zero Gate Voltage Drain Current V _{DS} = 60 V, V _{GS} = 0 V Gate-Body Leakage Current, Forward V _{GS} = 25 V, V _{DS} = 0 V Gate-Body Leakage Current, Reverse V _{GS} = -25 V, V _{DS} = 0 V Gate-Body Leakage Current, Reverse V _{GS} = -25 V, V _{DS} = 0 V Gate-Body Leakage Current, Reverse V _{GS} = -25 V, V _{DS} = 0 V Gate-Body Leakage Current, Reverse V _{GS} = -25 V, V _{DS} = 0 V Gate-Body Leakage Current, Reverse V _{GS} = -25 V, V _{DS} = 0 V Gate-Body Leakage Current, Reverse V _{GS} = -25 V, V _{DS} = 0 V Gate-Body Leakage Current, Reverse V _{DS} = 25 V, V _{DS} = 0 V Static Drain-Source V _{DS} = 25 V, V _{DS} = 0 V 0.018 Forward Transconductance V _{DS} = 25 V, V _{DS} = 0 V 22 GC Characteristics V _{DS} = 25 V, V _{DS} = 0 V 1180 Forward Transconductance V _{DS} = 25 V, V _{GS} = 0 V 440 Forward Transconductance V _{DS} = 25 V, V _{DS} = 0 V 1180 Forward Transconductance V _{DS} = 25 V, V _{DS} = 0 V 1180 Formation Delay Time V _{DD} = 30 V, I _D = 25 A 15 Formation Delay Time V _{DD} = 30 V, I _D = 25 A 15 Formation Gate Charge V _{DS} = 48 V, I _D = 50 A 105 Gate-Source Charge V _{DS} = 48 V, I _D = 50 A 31 Fource Diode Characteristics and Maximum Ratings V _{DS} = 10 V 13 Fource Diode Characteristics and Maximum Ratings V _{DS} = 0 V, I _S = 50 A Formation Drain-Source Diode Forward Current Formation Drain-Sou	bracteristics Drain-Source Breakdown Voltage $V_{GS} = 0 \text{ V}$, $I_D = 250 \mu\text{A}$ 60

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 230μH, I_{AS} = 50A, V_{DD} = 25V, R_G = 25 Ω , Starting T_J = 25°C 3. I_{SD} \leq 50A, di/dt \leq 300A/μs, V_{DD} \leq BV_{DSS}, Starting T_J = 25°C 4. Pulse Test : Pulse width \leq 300μs, Duty cycle \leq 2% 5. Essentially independent of operating temperature

Typical Characteristics

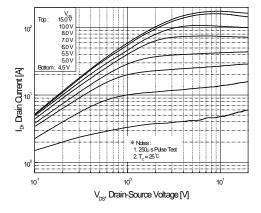


Figure 1. On-Region Characteristics

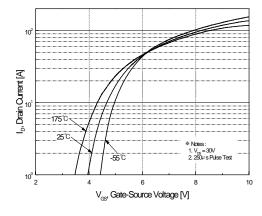


Figure 2. Transfer Characteristics

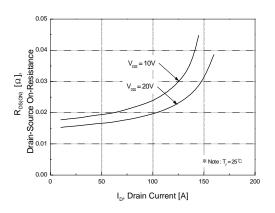


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

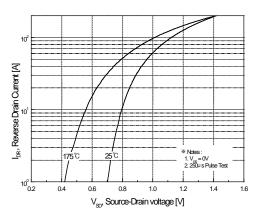


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

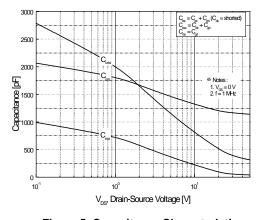


Figure 5. Capacitance Characteristics

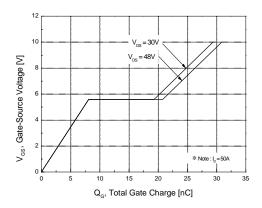
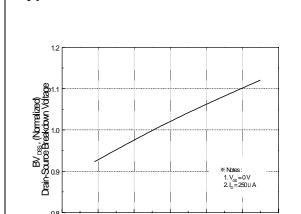


Figure 6. Gate Charge Characteristics

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Typical Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

T_J, Junction Temperature [°C]

150

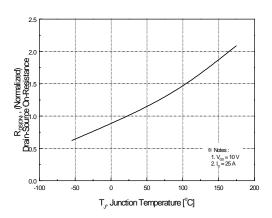


Figure 8. On-Resistance Variation vs. Temperature

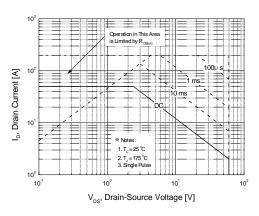


Figure 9. Maximum Safe Operating Area

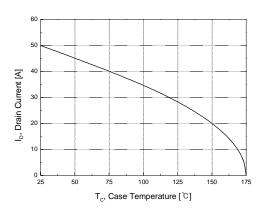


Figure 10. Maximum Drain Current vs. Case Temperature

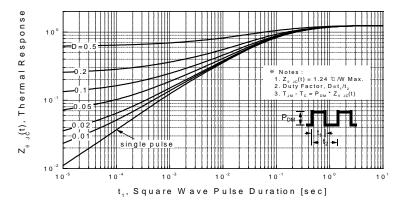
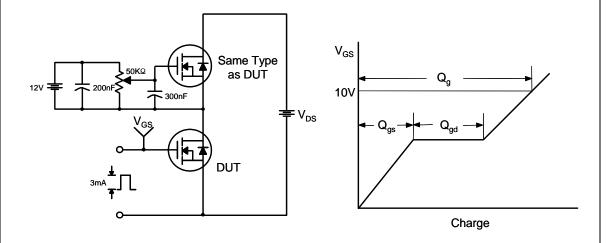


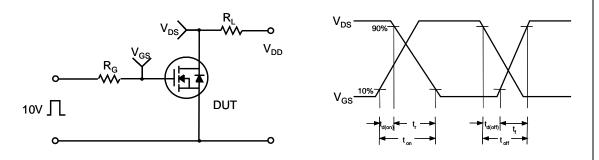
Figure 11. Transient Thermal Response Curve

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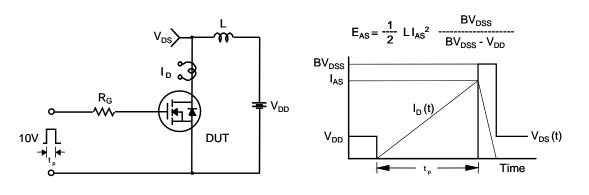
Gate Charge Test Circuit & Waveform



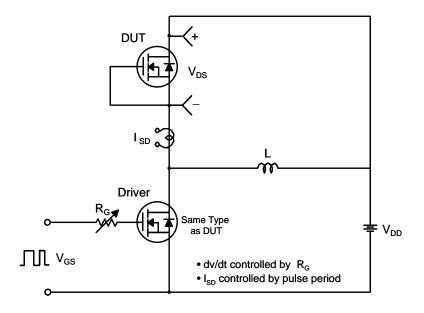
Resistive Switching Test Circuit & Waveforms

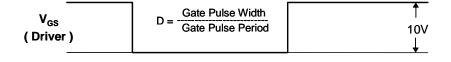


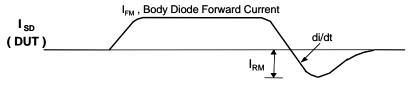
Unclamped Inductive Switching Test Circuit & Waveforms



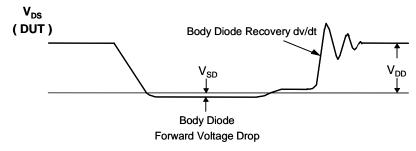
Peak Diode Recovery dv/dt Test Circuit & Waveforms







Body Diode Reverse Current

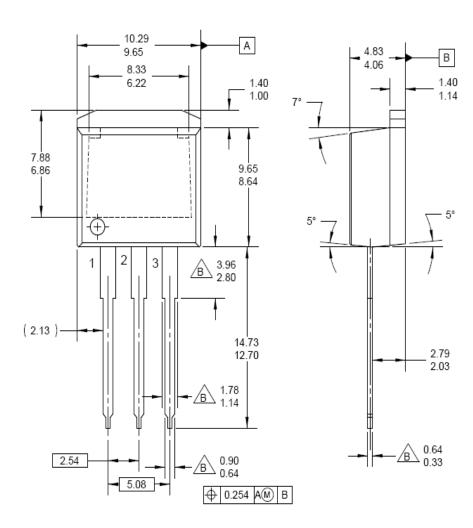


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Mechanical Dimensions D² - PAK -A-9.50 MIN 9.65 8.38 9.00 MIN 1.78 MAX 10.00 (2.12) -→ 0.25 M B AM - 5.08 -LAND PATTERN RECOMMENDATION -B-4.83 4.06 -6.22 MIN -1.65 1.14 6.86 MIN 15.88 14.61 SEE DETAIL A GAGE PLANE 0.25 0.10 B .25 MAX -SEATING PLANE A, ROTATED 90° SCALE: 10X Dimensions in Millimeters

Mechanical Dimensions

I² - PAK



Dimensions in Millimeters





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Rev. I37

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